



## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

## In re Application of:

Farnworth et al.

Serial No.: 10/669,949

Filed: September 24, 2003

**For:** WAFER-LEVEL TESTING APPARATUS AND METHOD

**Confirmation No.: 4767** 

Examiner: M. Trinh

**Group Art Unit: 2822** 

Attorney Docket No.: 2269-5467.1US

(02-0309.01/US)

**Notice of Allowance Mailed:** 

September 23, 2004

NOTICE OF EXPRESS MAILING

Express Mail Mailing Label Number: <u>EL994824581US</u>

Date of Deposit with USPS: December 22, 2004

Person making Deposit: Steven P. Wong

## AMENDMENT PURSUANT TO 37 C.F.R. § 1.312(a)

Mail Stop ISSUE FEE
Commissioner for Patents
P.O. Box 1450
Alexandria, Virginia 22313-1450

Sir:

Please amend the above-referenced application as follows:

Amendments to the Specification begin on page 3 of this paper.

Amendments to the Claims are reflected in the listing of claims which begins on page 5 of this paper.

Amendments to the Drawings appear on page 11of this paper and include both an attached replacement sheet and an annotated sheet showing changes.

Remarks begin on page 12 of this paper.